

Date: May 10, 2023

PCN No#: 051023-1

PCN Title: Additional new wafer source

Dear Customer:

This is an announcement of change(s) to products that are currently being offered by Micro Commercial Components Corp(MCC) .We request that you acknowledge receipt of this notification within 30 days of the date of this PCN. Please refer to the implementation date of this change as it is stated in the attached PCN form. Please contact your local sales representative to acknowledge receipt of this PCN.

If you have any questions about PCN's products, please contact your local sales representative.

Sincerely,

MCC PCN Team



PRODUCT CHANGE NOTICE

Notification Date	Plan Effective Da	te Change Type	Classification	PCN No	
May 10, 2023	Aug 10,2023	Add new wafer source	Major	051023-1	
		TITLE			
Additional new wafer	source				
		DESCRIPTION OF CHANGE			
In order to improve p been finished and t	product features, MCC he result showed tha	has determined to add a new wafer source. t the parts with new wafer exactly met our spe	nternal qualification process cification.	had	
		IMPACT			
		Electrical Characteristics Comparison.			
		PRODUCTS AFFECTED			
SICU0660P-TP/SIC	0660P-BP				
		WEB LINKS			
Terms And Conditi	ons: h	https://www.mccsemi.com/Home/TermsAndConditions			
For More Information	on Contact:	https://www.mccsemi.com/Contact/Index			
Products:	ł	ttps://www.mccsemi.com/ProductCategories			
		DISCLAIMER			
		DISCLAIMER ontacted in writing within 30 days of the po	esting of this notice, all ch	anges	



SICU0660P-TP/SIC0660P-BP

3100000	P-1P/SIC0660P-B	iP			
Table B- Electrical Characteristics Comparison					
ltem	Parameters	Test Conditions	Current	New	Unit
1	Die size	Vernier Caliper	1.1*2.27	1.6*1.6	mm
2	VF	IF=6A	1.39	1.32	V
3	IR	VR=650V	3.8	0.5	uA
4	BV	IT=250uA	800	900	V
5	QC	VR=400V	15.6	25	nC

Table E- Marking Code Comparison				
	Current	New	Remark	
Marking Code	MCC XXXXX	MCC XXXXX YYWW	Add date code YY year WW week	



Reliability Report

Part Number: SICPT4060DY-BP (SICU0660P-TP & SIC0660P-BP refer) Date: 2022-10-25 Test Results : <u>PASS</u>

Test Item	Conditions	Duration	Quantity	Rejects
TEST Pre- and Post-Stress Electrical Test	T _a = 25 °C	N/A	all parts	see below
LTSL Low Temperature Storage Life	JESD22-A11 -55 [°] C	1000 hours	77Pcs	0
HTRB High Temperature Reverse Bias	MIL-STD-750 Method 1038 T _j = T _{jmax} , 80% VR	1000 hours	77Pcs	0
TC Temperature Cycling	JESD22-A104 -55℃(+0,-10)/15Min~ 150(+15,-0)/15Min,	1000Cycles (500hours)	77Pcs	0
UHAST Un-bias High accelerated temperature and humidity stress test	JESD22A-118 T _a = 130 °C±2 [°] C,RH = 85 ±5%	96 hours	77Pcs	0
HV-H3TRB High Humidity High Temperature Reverse Bias	JESD22-A101 T₄ = 85 °C±2℃,RH = 85%±5%, 80 % VR	1000 hours	77Pcs	0
IOL Intermittent Operating Life	MIL-STD-750 Method 1037 ON 2Min/OFF 2min, devices powered to insure $\Delta T_j \ge 100 \text{ °C}$	15000 cycles (1000 hours)	77Pcs	0
RSH Resistance to Solder Heat	JESD22-B106 260 °C (+5, -0)	10 s	30Pcs	0
SD Solderability	J-STD-002 235 °C ± 5 °C	3 s	10Pcs	0